


<b>Search Notes</b>  	<b>Application/Control No.</b>  10590768	<b>Applicant(s)/Patent Under Reexamination</b>  JENSEN ET AL.
	<b>Examiner</b>  Young J Kim	<b>Art Unit</b>  1637

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SEARCH NOTES		
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Patent Databases (USPT, USPGP, EPO, JP0, DERWENT, IBM-TDB) - see enclosed for text search strategy	8/6/2009	/YJK/

INTERFERENCE SEARCH			
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	/Young J Kim/ Primary Examiner.Art Unit 1637
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